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In re Application of: Zongtao GE

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Examiner: TO BE ASSIGNED


For: Phase Shift Fringe Analysis Method and Apparatus Using the Same

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U.S. PATENT DOCUMENTS			
Examiner Initials*	U.S. Patent Document Number	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY

FOREIGN PATENT DOCUMENTS				
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OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS		
Examiners Initials*	Include Author (CAPITAL LETTERS), title of article, book, magazine, etc. date, page(s), volume-issue number(s), publisher, city and/or country where published	T**
ML	MITSUO TAKEDA, "Subfringe Interferometry Fundamentals", Kogaku, February 1984, pp. 55-65, Vol. 13, No. 1, Japan	
ML	KATHERINE CREATH, "Phase-Measurement Interferometry Techniques", Progress in Optics, E. Wolf, Editor, 1988, pp. 349-393, Vol. XXVI, Elsevier Science Publishers B.V., New York, U.S.A.	

Examiner Signature		Date Considered	April 21, 2004
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*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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